

Low Gain Avalanche Diodes Technology: state of the art and new developments

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Abstract

Low Gain Avalanche Diodes (LGAD) are considered one of the most promising solutions for timing application in HEP experiments and 4dimensional tracking, due to some important advantages: larger internal signal, better time resolution and higher radiation hardness with respect to standard p-i-n based sensors.

Novel design schemes and microfabrication technologies are under investigation, mainly focused on improving two key aspects of the technology: i) increasing the radiation hardness at fluence higher than 3e15 neq/cm² and ii) improving the spatial resolution moving through fine-pixellated and high-fill-factor sensor designs. To improve the spatial resolution, novel segmentations schemes

have been developed: i) Trench-Isolated LGAD (**TI-LGAD**) exploits narrow trenches, physically etched in the silicon to reduce the deadborder area of the pixel, while **AC- and DC-coupled Resistive Silicon Detectors** (RSD and DC-RSD, respectively) exploit signal sharing among multiple pads. Both the technologies allow to reach excellent spatial resolution without spoiling time resolution.

To improve the radiation hardness at high fluences, Carbon **co-implantation** shown to be effective in preserving the excellent time resolution of LGADs up to fluence 2e15 neq/cm². Novel techniques like **compensated doping** profiles are under investigations and could be effective in leading the radiation hardens of these devices up to unprecedent levels.

Trench-Isolated LGAD

[1] G. Paternoster

Radiation Hardening

[2] M. Ferrero

Isolation Trench n⁺/p⁺ multiplication region Epi-silicon (p⁻) Support wafer (p⁺) * Junction Termination Edge (JTE) and p-stop are replaced by a single trench. * Reduced inter-pixel region with no gain (

- 5 μm)
 * Arrays with 50 -55 μm anf FF > 85% (compatible with Medipix/Timepix)
- * Same time resolution of standard LGAD
- * Same radiation resistance of standard LGAD

Inter-pixel width measured with laser scan







- LGADs suffer from gain loss at high fluence (>10¹⁴ neq/cm²) due to "acceptor removal" effect
- Carbon co-implantation allows to mitigate the gain-loss and preserve time resolution



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							-
							-
2							-
							10
							10
							12

15x15 array for ATLAS HGTD



 Excellent time resolution (< 30ps, for MIP) up to 1.5e15 neq/cm²
 Reduced bias voltage

Radiation Hardening at extreme fluences

[7] V. Sola

GOAL: operate LGADs at fluence > 10^{16} neq/cm² (not possible with the current technology due to: induced defects and traps, change in the bulk doping, gain-loss (acceptor removal)

AC- and DC- Resistive Silicon Detectors

[3] N. Cartiglia, [4] M. tornago [5] M. Mandurrino



- * RSD readout scheme exploits signal sharing among pads to reach high spatial resolution keeping a coarse pad segmentation
- * 100% fill-factor
- Preserve time resolution of LGADs
- * Spatial resolution (sigma) $\sim 13 \ \mu m$ with a 450 μm pitch



AC-RSD with

"cross-shaped" pads





DOPING COMPENSATION: Use the interplay between acceptor and donor removal to keep a constant gain-layer doping density



References

[1] G. Paternoster, EDL 2020, DOI: 10.1109/LED.2020.2991351
[2] M. Ferrero, NIMA 2018, DOI: 10.1016/j.nima.2018.11.121
[4] N. Cartiglia, presented at Trento Workshop (TREDI) 2022
[5] M. Tornago, NIMA 2021 DOI: 10.1016/j.nima.2021.165319
[6] M. Mandurrino, arxiv.org/abs/2111.14235
[7] V. Sola, presented at Trento Workshop (TREDI) 2022